

### MOS Field Effect Power Transistors

2SK3062

# SWITCHING N-CHANNEL POWER MOS FET INDUSTRIAL USE

#### **DESCRIPTION**

This product is N-Channel MOS Field Effect Transistor designed for high current switching applications.

#### **FEATURES**

- $\circ$  Super Low On-State Resistance RDS(on)1 = 9m $\Omega$  Max. (Vgs=10V,ID=35A) RDS(on)2 =14m $\Omega$  Max. (Vgs= 4V,ID=35A)
- Low Ciss Ciss = 5020 pF Typ.
- · Built-in Gate Protection Diode

## ABSOLUTE MAXIMUM RATINGS(Ta=25°C)

Drain to Source Voltage	Voss	60	V
Gate to Source Voltage	$V_{GSS}$	± 20	V
Drain Current(DC)	Ιό(ος)	± 70	Α
Drain Current(pulse)*	D(pulse)	±280	Α
Total Power Dissipation(T <sub>c</sub> =25°C)	Рт	100	W
Total Power Dissipation(Ta=25°C)	Рт	1.5	W
Channel Temperature	Tch	150	°C
Storage Temperature	$T_{\text{stg}}$	-55 <b>~</b> +150	°C
* PW≤10μs,Duty Cycle≤1%			

#### THERMAL RESISTANCE

Channel to Case	Rth(ch-c)	1.25	°C/W
Channel to Ambient	Rth(ch-a)	83.3	°C/W

**PACKAGE DIMENSIONS** (in millimeter) MP-25 (TO-220) MP-25Z (SURFACE MOUNT TYPE) Drain Body Diode Gate **Gate Protection** Diode Source

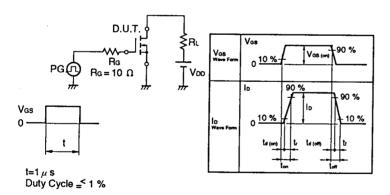
The diode connected between the gate and source of the transistor serves as a protector against ESD. When this deveice acutally used, an additional protection circuit is externally required if a voltage exceeding the rated voltage may be applied to this device.

This information in this document is being issued in advance of the production cycle for the device. The parameter for the device may change before final production or NEC Corporation, at its own discretion, may withdraw the device prior to its production.

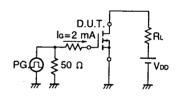
# ELECTRICAL CHARACTERISTICS(Ta=25°C)

CHARACTERISTICS	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT
Drain to Source	RDS(on)1	Vgs=10V,lp=35A		6.3	9.0	mΩ
On-state Resistance	RDS(on)2	Vgs= 4V, lp=35A		9.6	14	mΩ
Gate to Source Cutoff Voltage	V <sub>GS(off)</sub>	Vos=10V,lo=1mA	1.0	1.5	2.0	V
Forward Transfer Admittance	y <sub>fs</sub>	Vps=10V,lp=35A	20	75		S
Drain Leakage Current	loss	Vos=60V,Vgs=0			10	μΑ
Gate to Source Leakage Current	lgss	Vgs=±20V,Vps=0			±10	μΑ
Input Capacitance	Ciss	V <sub>DS</sub> =10V		5020		pF
Output Capacitance	Coss	V <sub>G</sub> s=0		1300		pF
Reverse Transfer Capacitance	Crss	f=1MHz		460		pF
Turn-On Delay Time	td(on)	lo=35A		60		nS
Rise Time	tr	V <sub>GS(on)</sub> =10V	•	750		nS
Turn-Off Delay Time	td(off)	V <sub>DD</sub> =30V		330		nS
Fall Time	tr	Rg=10Ω		410		nS
Total Gate Charge	Q <sub>G</sub>	ID=70A		90		nC
Gate to Source Charge	Qgs	V <sub>DD</sub> =48V		10		nC
Gate to Drain Charge	Q <sub>GD</sub>	V <sub>G</sub> s=10V		30		nC
Body Diode Forward Voltage	V <sub>F(S-D)</sub>	I <sub>F</sub> =70A,V <sub>GS</sub> =0		1.1		V
Reverse Recovery Time	trr	I <sub>F</sub> =70A,V <sub>G</sub> s=0		90		ns
Reverse Recovery Charge	Qrr	di/dt=100A/μs		20		nC

Test Circuit 1 Switching Time



Test Circuit 2 Gate Charge



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Anti-radioactive design is not implemented in this product.